

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LIN ET AL.	
		Examiner Arnel C. Lavarias	Art Unit 2872	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0057486	05-2002	Tanaka, Satoru	359/292
	B	US-5,684,611	11-1997	Rakuljic et al.	359/7
	C	US-2003/0007129	01-2003	Ashizaki, Koji	353/7
	D	US-3,694,657	09-1972	Brooks, Robert E.	250/216
	E	US-5,481,523	01-1996	Dewald, Duane S.	369/103
	F	US-3,615,123	10-1971	Wuerker, R. F.	359/24
	G	US-2002/0114027	08-2002	Horimai, Hideyoshi	359/11
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	<i>None</i>				
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	<i>None</i>
	V	
	W	
	X	

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